



## CLUSTER DETECTOR TEST REPORT

**CLUSTER DETECTOR No. 11**  
**Test carried on 13.12.11 – 14.12.11**

Ch.	HEX	U <sub>op</sub> [V]	U <sub>op</sub> – 500 V		U <sub>op</sub>			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{FWHM}$	Pos. [Ch.]	FWHM [keV]
A	107	4000	2.25	n.c.	2.15	n.c.	6265	
B	173	4000	2.12	n.c.	2.03	n.c.	6331	
C	103	3500	2.09	n.c.	2.11	n.c.	6267	
D	109	4000	1.91	n.c.	1.94	n.c.	8725	
E	139	4000	2.02	n.c.	1.98	n.c.	6108	
F	127	4000	2.00	n.c.	1.95	n.c.	6821	
G	106	4000	2.03	n.c.	2.00	n.c.	6975	

**Operational Temperature: -170.2 °C**

**Date: 14.12.2011**

**Tested by:**  
**/I.Kojouharov/**

**Assembly and test remarks:**

Regular test after assembly at RIKEN

**Test Equipment:**

HV – ORTEC 660

Main Amplifier – ORTEC 671,  $\tau = 6 \mu\text{s}$ , Gain 100 x 0.72

ADC – 4801A (RIKEN), MCA - PC98B

Source -  $^{60}\text{Co}$